



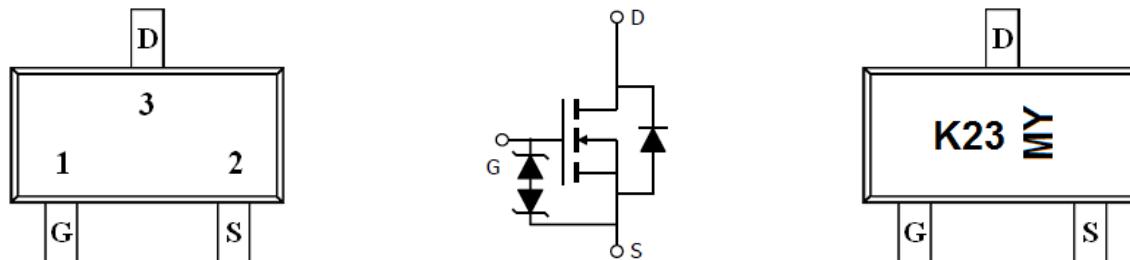
## General Description

AFN123WS, N-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent  $R_{DS(ON)}$ , low gate charge. These devices are particularly suited for low voltage power management, such as smart phone and notebook computer and other battery powered circuits, and low in-line power loss are needed in commercial industrial surface mount applications.

## Features

- 100V/0.17A ,  $R_{DS(ON)}=5.8\Omega @ V_{GS}=10V$
- 100V/0.17A ,  $R_{DS(ON)}=6.8\Omega @ V_{GS}=4.5V$
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability
- ESD Protection Diode design-in
- SOT-323 package design

## Pin Description ( SOT-323 )



## Application

- Drivers: Relays, Solenoids, Lamps, Hammers, Display, Memories, Transistors, etc.
- High saturation current capability. Direct Logic-Level Interface: TTL/CMOS
- Battery Operated Systems
- Solid-State Relays

## Pin Define

Pin	Symbol	Description
1	G	Gate
2	S	Source
3	D	Drain

## Ordering Information

Part Ordering No.	Part Marking	Package	Unit	Quantity
AFN123WSS32RG	K23YM	SOT-323	Tape & Reel	3000 EA

- ※ K23 Parts code
- ※ Y Year code ( 0 ~ 9 )
- ※ M Month code ( A ~ L = 1 ~ 12 )
- ※ AFN123WSS32RG : 7" Tape & Reel ; Pb- Free ; Halogen -Free



### Absolute Maximum Ratings

( $T_A=25^\circ\text{C}$  Unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	100	V
Gate –Source Voltage	$V_{GSS}$	$\pm 20$	V
Continuous Drain Current( $T_J=150^\circ\text{C}$ )	$I_D$	0.17	A
		0.17	
Pulsed Drain Current	$I_{DM}$	0.68	A
Continuous Source Current(Diode Conduction)	$I_S$	0.4	A
Power Dissipation	$P_D$	0.35	W
		0.22	
Operating Junction Temperature	$T_J$	150	150
Storage Temperature Range	$T_{STG}$	-55/150	-55/150
Thermal Resistance-Junction to Ambient	$R_{\theta JA}$	120	120

### Electrical Characteristics

( $T_A=25^\circ\text{C}$  Unless otherwise noted)

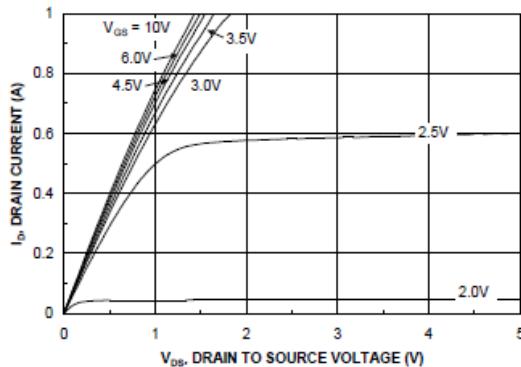
Parameter	Symbol	Conditions	Min.	Typ	Max.	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0		3.0	
Gate Leakage Current	$I_{GSS}$	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			10	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=80\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
		$V_{DS}=80\text{V}, V_{GS}=0\text{V}$ $T_J=85^\circ\text{C}$			10	
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=0.17\text{A}$		4.0	5.8	$\Omega$
		$V_{GS}=4.5\text{V}, I_D=0.17\text{A}$		4.6	6.8	
Forward Transconductance	$g_{FS}$	$V_{DS}=10\text{V}, I_D=0.17\text{A}$		0.8		S
Diode Forward Voltage	$V_{SD}$	$I_S=0.17\text{A}, V_{GS}=0\text{V}$		0.75	1.3	V
<b>Dynamic</b>						
Total Gate Charge	$Q_g$	$V_{DS}=30\text{V}, V_{GS}=10\text{V}$		1.8	3.5	nC
Gate-Source Charge	$Q_{gs}$			0.2		
Gate-Drain Charge	$Q_{gd}$			0.3		
Input Capacitance	$C_{iss}$	$V_{DS}=25\text{V}, V_{GS}=0\text{V}$ $f=1\text{MHz}$		70		pF
Output Capacitance	$C_{oss}$			8		
Reverse Transfer Capacitance	$C_{rss}$			5		
Turn-On Time	$t_{d(on)}$	$V_{DD}=30\text{V}, R_G=50\Omega$		5	10	ns
	$t_r$			5	10	
Turn-Off Time	$t_{d(off)}$			7	15	
	$t_f$			10	20	



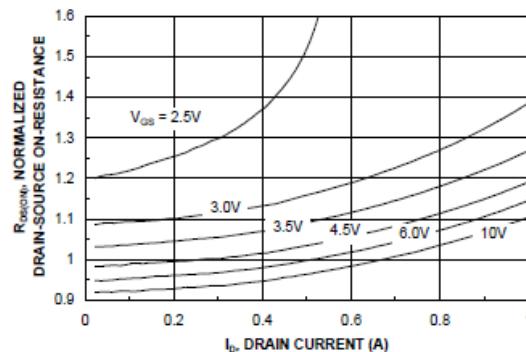
**Alfa-MOS  
Technology**

**AFN123WS  
100V N-Channel  
Enhancement Mode MOSFET**

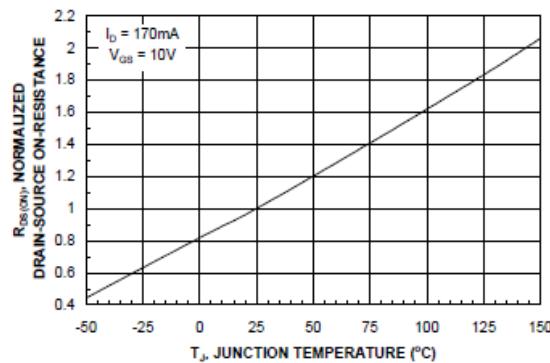
### Typical Characteristics



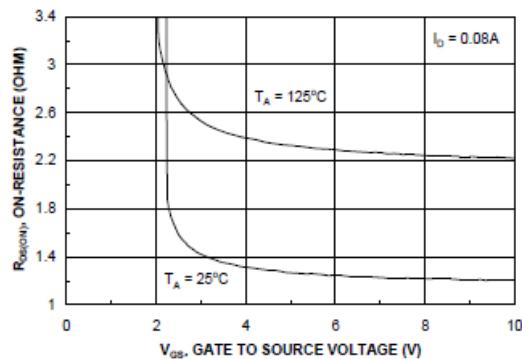
On-Region Characteristics



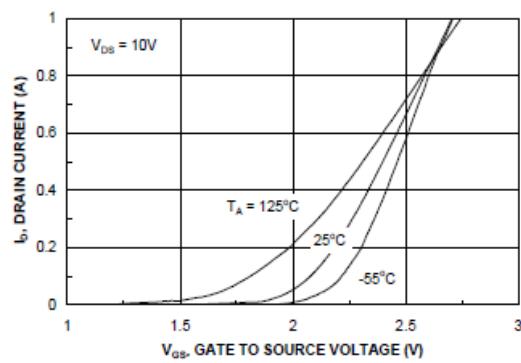
On-Resistance Variation with  
Drain Current and Gate Voltage



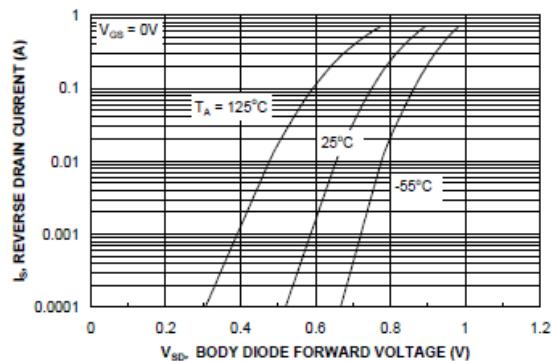
On-Resistance Variation with Temperature



On-Resistance Variation with  
Gate-to-Source Voltage



Transfer Characteristics



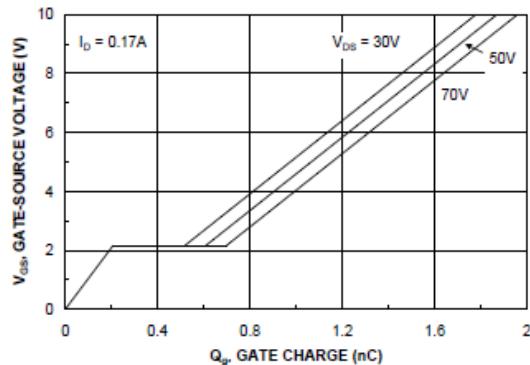
Body Diode Forward Voltage Variation  
with Source Current and Temperature



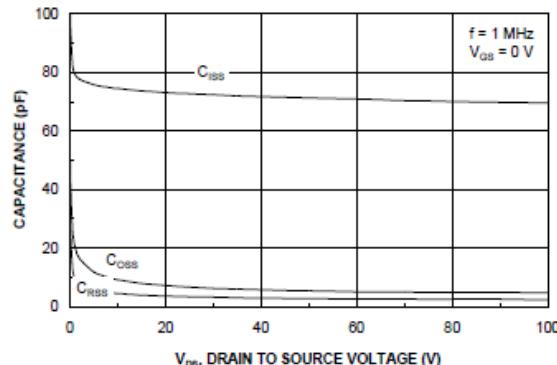
# Alfa-MOS Technology

**AFN123WS**  
**100V N-Channel**  
**Enhancement Mode MOSFET**

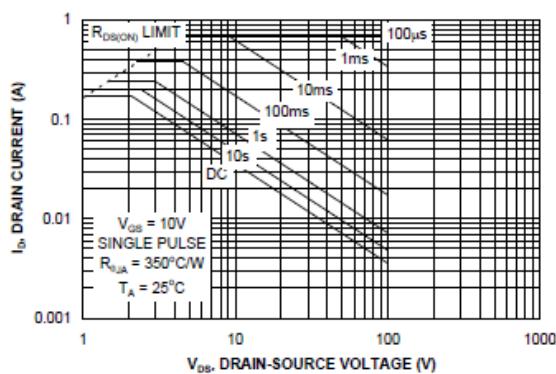
## Typical Characteristics



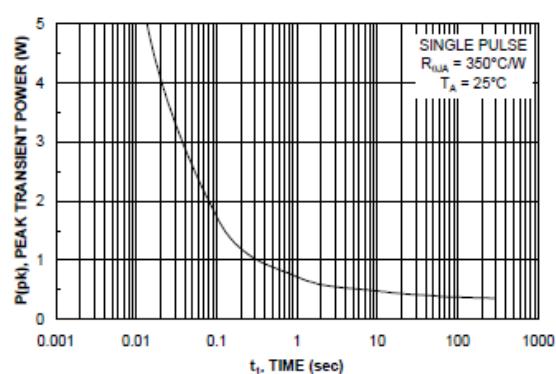
Gate Charge Characteristics



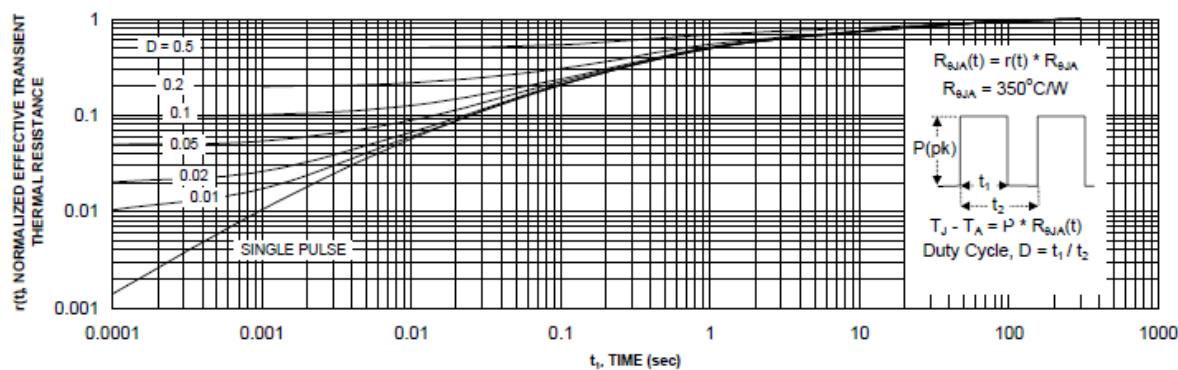
Capacitance Characteristics



Maximum Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve, Junction to Ambient

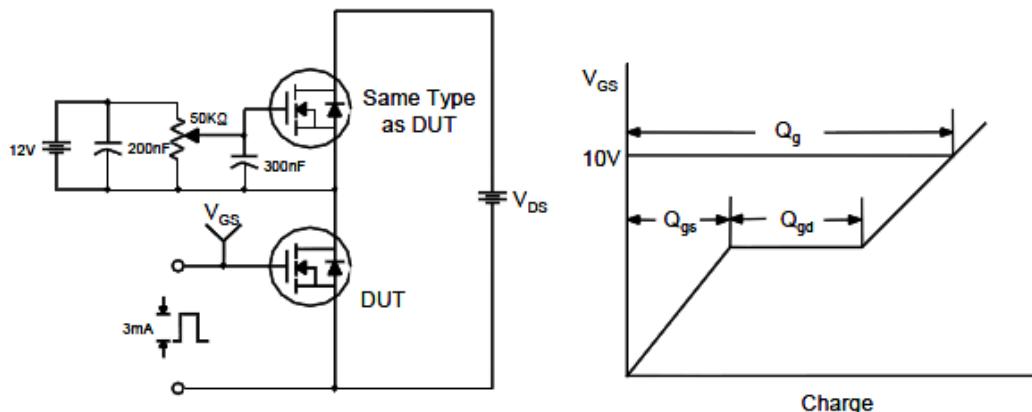


**Alfa-MOS  
Technology**

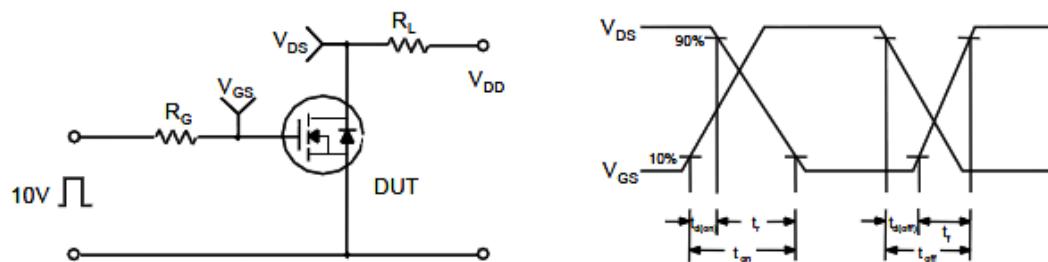
**AFN123WS  
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## Typical Characteristics

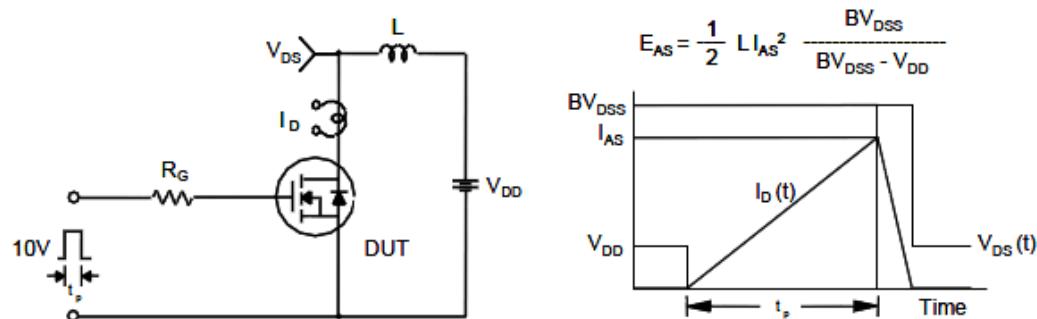
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

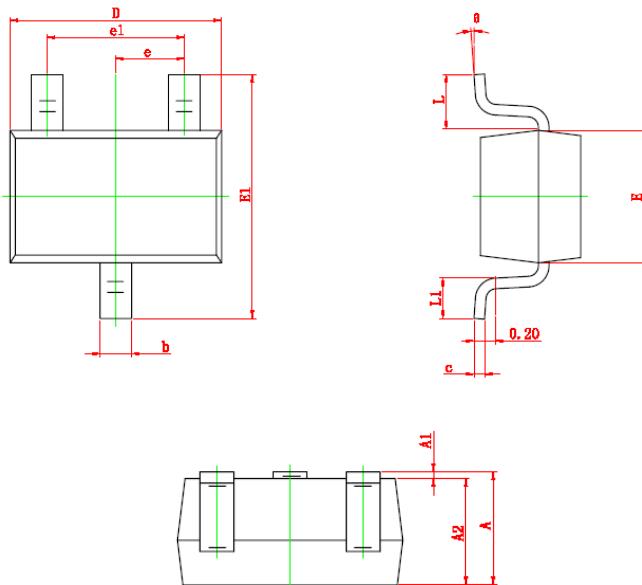


Unclamped Inductive Switching Test Circuit & Waveforms





**Package Information ( SOT-323 )**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.200	0.400	0.008	0.016
c	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
E	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
e	0.650 TYP		0.026 TYP	
e1	1.200	1.400	0.047	0.055
L	0.525 REF		0.021 REF	
L1	0.260	0.460	0.010	0.018
θ	0°	8°	0°	8°

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